Application/Control No.	Applicant(s)/Patent under Reexamination	
10/747,744	WU ET AL.	•
Examiner	Art Unit	
W. Patty Chen	2871	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
key words search of all databases in EAST	5/16/2006	WPC
reviewed previously cited references	5/16/2006	WPC